

# FQB11P06 / FQI11P06 **P-Channel QFET MOSFET**

-60 V, -11.4 A, 175 mΩ

## Description

This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

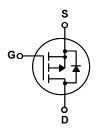


#### **Features**

- -11.4 A, -60 V,  $R_{DS(on)}$  = 175 m $\Omega$  (Max) @ $V_{GS}$  = -10 V,  $I_D = -5.7 A$
- Low Gate Charge (Typ. 13 nC)
- Low Crss (Typ. 45 pF)
- 100% Avalanche Tested
- 175°C Maximum Junction Temperature Rating







## Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQB11P06 / FQI11P06	Unit
$V_{DSS}$	Drain-Source Voltage		-60	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C	<b>(</b> )	-11.4	Α
	- Continuous (T <sub>C</sub> = 100°C)		-8.05	Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	-45.6	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 25	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	160	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	-11.4	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	5.3	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-7.0	V/ns
$P_{D}$	Power Dissipation (T <sub>A</sub> = 25°C) *		3.13	W
	Power Dissipation (T <sub>C</sub> = 25°C)		53	W
	- Derate above 25°C		0.35	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +175	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

### **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.85	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-60			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = -250 μA, Referenced to 25°C		-0.07		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -60 V, V <sub>GS</sub> = 0 V			-1	μΑ
		V <sub>DS</sub> = -48 V, T <sub>C</sub> = 150°C			-10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = -25 V, V <sub>DS</sub> = 0 V			-100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = 25 V, V <sub>DS</sub> = 0 V			100	nA
On Cha	aracteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-2.0		-4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -5.7 A		0.14	0.175	Ω
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = -30 \text{ V}, I_D = -5.7 \text{ A}$ (Note 4)		5.1		S
C <sub>iss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		420 195 45	550 250 60	pF pF pF
C <sub>rss</sub>	Reverse Transfer Capacitance			45	60	pF
Switch	ing Characteristics					
Switch	ing Characteristics					
	Turn-On Delay Time	V <sub>DD</sub> = -30 V. I <sub>D</sub> = -5.7 A.		6.5	25	ns
t <sub>d(on)</sub>	, <del>-</del>	$V_{DD} = -30 \text{ V}, I_{D} = -5.7 \text{ A},$ $R_{G} = 25 \Omega$		6.5 40	25 90	ns ns
t <sub>d(on)</sub>	Turn-On Delay Time	$R_G = 25 \Omega$			_	
t <sub>d(on)</sub> t <sub>r</sub> t <sub>d(off)</sub>	Turn-On Delay Time Turn-On Rise Time	00 10		40	90	ns
t <sub>d(on)</sub> t <sub>r</sub> t <sub>d(off)</sub>	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time	$R_G = 25 \Omega$		40 15	90	ns ns
t <sub>d(on)</sub> t <sub>r</sub> t <sub>d(off)</sub> t <sub>f</sub> Q <sub>g</sub>	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time	$R_G$ = 25 $\Omega$ (Note 4, 5)		40 15 45	90 40 100	ns ns ns
$t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$ $Q_g$ $Q_{gs}$	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge	$R_G = 25 \Omega$ (Note 4, 5) $V_{DS} = -48 \text{ V}, I_D = -11.4 \text{ A},$		40 15 45 13	90 40 100 17	ns ns ns nC
td(on) tr tr td(off) tf Qg Qgs Qgd	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge	$R_{G}$ = 25 $\Omega$ (Note 4, 5) $V_{DS}$ = -48 V, $I_{D}$ = -11.4 A, $V_{GS}$ = -10 V (Note 4, 5)	   	40 15 45 13 2.0	90 40 100 17 	ns ns ns
t <sub>d(on)</sub> t <sub>r</sub> t <sub>t</sub> Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge	$R_G = 25~\Omega \label{eq:reconstruction}$ (Note 4, 5) $V_{DS} = -48~V,~I_D = -11.4~A,~V_{GS} = -10~V \label{eq:reconstruction}$ (Note 4, 5) and Maximum Ratings	   	40 15 45 13 2.0	90 40 100 17 	ns ns ns nC
t <sub>d(on)</sub> t <sub>r</sub> t <sub>d(off)</sub> t <sub>f</sub> Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub> Drain-S	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge	$R_G = 25 \Omega$ (Note 4, 5) $V_{DS} = -48 \text{ V}, I_D = -11.4 \text{ A}, V_{GS} = -10 \text{ V}$ (Note 4, 5)  and Maximum Ratings ode Forward Current	   	40 15 45 13 2.0 6.3	90 40 100 17 	ns ns ns nC nC
td(on) tr td(off) tf Qg Qgs Qgd  Drain-S	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge  Source Diode Characteristics and Maximum Continuous Drain-Source Diode	$R_G = 25 \Omega$ (Note 4, 5) $V_{DS} = -48 \text{ V}, I_D = -11.4 \text{ A}, V_{GS} = -10 \text{ V}$ (Note 4, 5)  and Maximum Ratings ode Forward Current		40 15 45 13 2.0 6.3	90 40 100 17  	ns ns ns nC nC
t <sub>d(on)</sub> t <sub>r</sub> t <sub>r</sub> t <sub>d(off)</sub> t <sub>f</sub> Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge  Source Diode Characteristics au Maximum Continuous Drain-Source Diode F	$R_G = 25 \Omega$ (Note 4, 5) $V_{DS} = -48 \text{ V}, I_D = -11.4 \text{ A},$ $V_{GS} = -10 \text{ V}$ (Note 4, 5)  and Maximum Ratings  and Forward Current  Forward Current	   	40 15 45 13 2.0 6.3	90 40 100 17   -11.4 -45.6	ns ns nc nC nC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 1.44mH, I $_{AS}$  = -11.4A, V $_{DD}$  = -25V, R $_{G}$  = 25  $\Omega$ , Starting T $_{J}$  = 25°C 3. I $_{SD}$  ≤ -11.4A, di/dt ≤ 300 $\Delta$ Iµs, V $_{DD}$  ≤ BV $_{DSS}$ , Starting T $_{J}$  = 25°C 4. Pulse Test : Pulse width ≤ 300 $\mu$ s, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

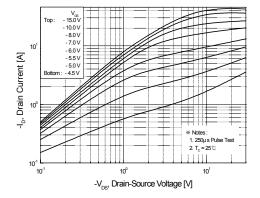


Figure 1. On-Region Characteristics

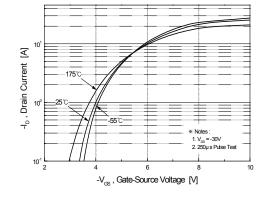


Figure 2. Transfer Characteristics

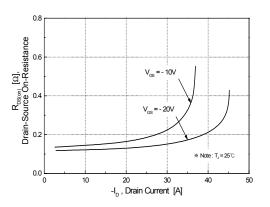


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

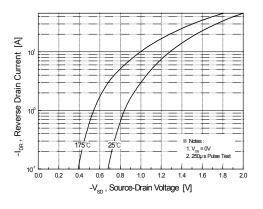


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

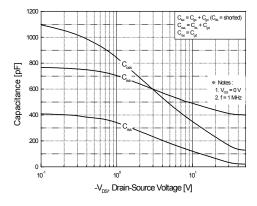


Figure 5. Capacitance Characteristics

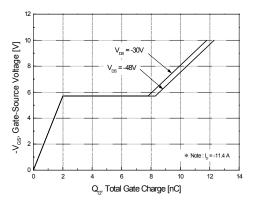


Figure 6. Gate Charge Characteristics

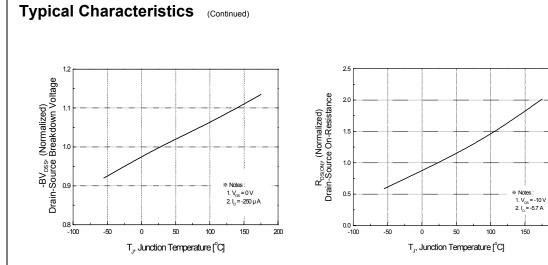


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature

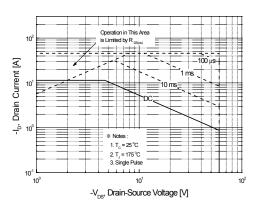


Figure 9. Maximum Safe Operating Area

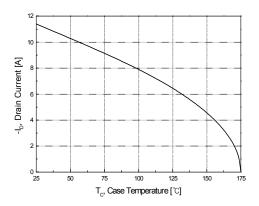


Figure 10. Maximum Drain Current vs. Case Temperature

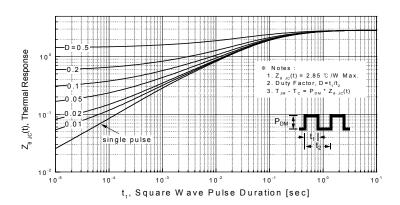
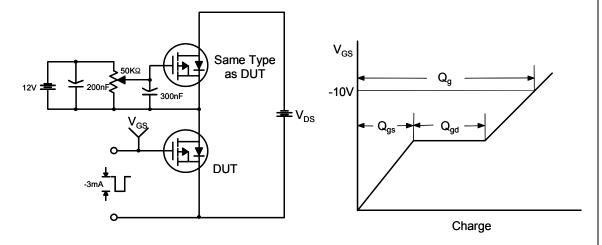
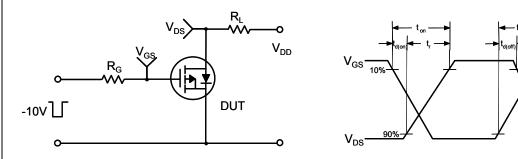


Figure 11. Transient Thermal Response Curve

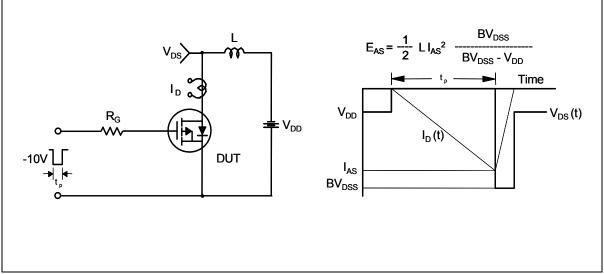
#### **Gate Charge Test Circuit & Waveform**



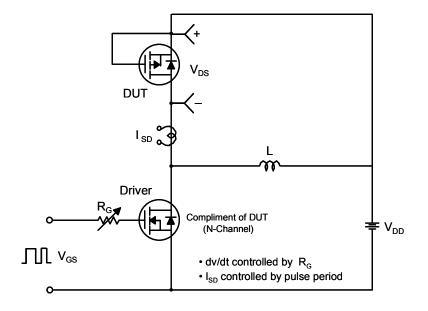
#### **Resistive Switching Test Circuit & Waveforms**

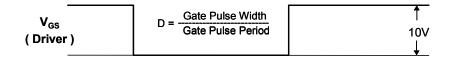


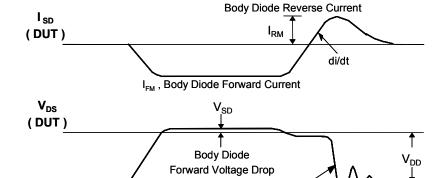
#### **Unclamped Inductive Switching Test Circuit & Waveforms**



#### Peak Diode Recovery dv/dt Test Circuit & Waveforms







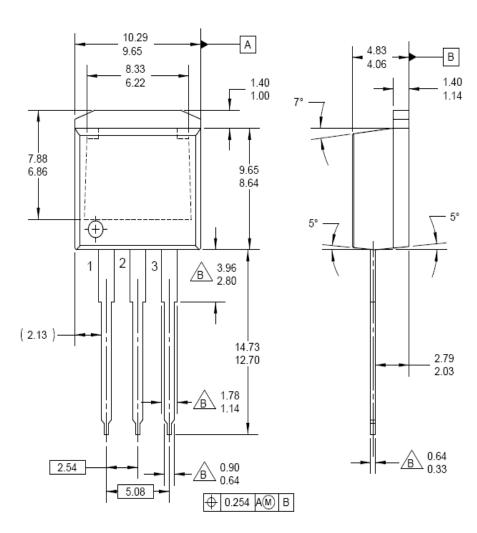
Body Diode Recovery dv/dt

# **Mechanical Dimensions** D<sup>2</sup> - PAK -A-9.65 8.38 9.00 MIN 1.78 MAX 10.00 MIN (2.12)→ -1.50 MIN → 0.25 M B AM 5.08 5.08 LAND PATTERN RECOMMENDATION -B-6.22 MIN 1.65 1.14 6.86 MIN 15.88 14.61 SEE DETAIL A GAGE PLANE 0.25 △ 0.10 B .25 MAX -SEATING PLANE **DETAIL**

Dimensions in Millimeters

### **Mechanical Dimensions**

I<sup>2</sup> - PAK



Dimensions in Millimeters





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No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

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